

Notice of References Cited	Application/Control No. 10/630,949	Applicant(s)/Patent Under Reexamination REED ET AL.	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,150,843	11-2000	Shiffer et al.	326/80
*	B	US-6,342,996	01-2002	Drapkin et al.	361/91.1
*	C	US-6,441,670	08-2002	Coughlin et al.	327/323
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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